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High Resolution On-Chip Measurement Technique -New Analog-BIST Scheme Using Comparator Delay-

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Research Objective:

Development of on-chip measurement circuit for ***Milli-Volt order*** *high resolution voltage detection*

Innovation:

- ***Time-domain signal processing***

The smaller ΔVin is, the longer the delay is.
⇒ *The easier its detection is.*

- ***Simple*** *circuit implementation*

Application:

Analog Built-In-Self-Test & Measurement scheme for high-precision Digital-to-Analog Converters

Concept of proposed BIST scheme